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Bias-Dependent Charge Accumulation in Pentacene-based Thin-Film Transistors

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Abstract

In this paper, we have demonstrated the current increase with repeated measurements of I_d - V_{ds} curves with different V_g values which results from the non-uniform carrier accumulation in the channel region of a pentacene-based thin film transistor (TFT). The mobility of our device reaches $0.07 \text{ cm}^2/\text{Vs}$ even the substrate was not heated during pentacene deposition. Besides, the devices show good air-stable properties. The magnitude of I_d decreased less than 30% after exposure in air for 2 weeks. By repeating the I_d - V_{ds} measurements from 0 to -50 V with the V_g values of 0, -10, -20, -30, -40, and -50 V for 10 minutes, we observed a four times current increase from -0.75 to -2.8 μA at $V_g = -50\text{V}$ and $V_{ds} = -50\text{V}$. The current increase comes from the holes accumulation near the drain. When the source and drain were exchanged, the current decreases to the 0.08 μA . After another 10 minutes operation, the current will recover back to the original values. Such a process is reversible and shows the potential of the memory device base on this pentacene transistor.

Key words : Organic thin-film transistor; Mobility; Carrier transport